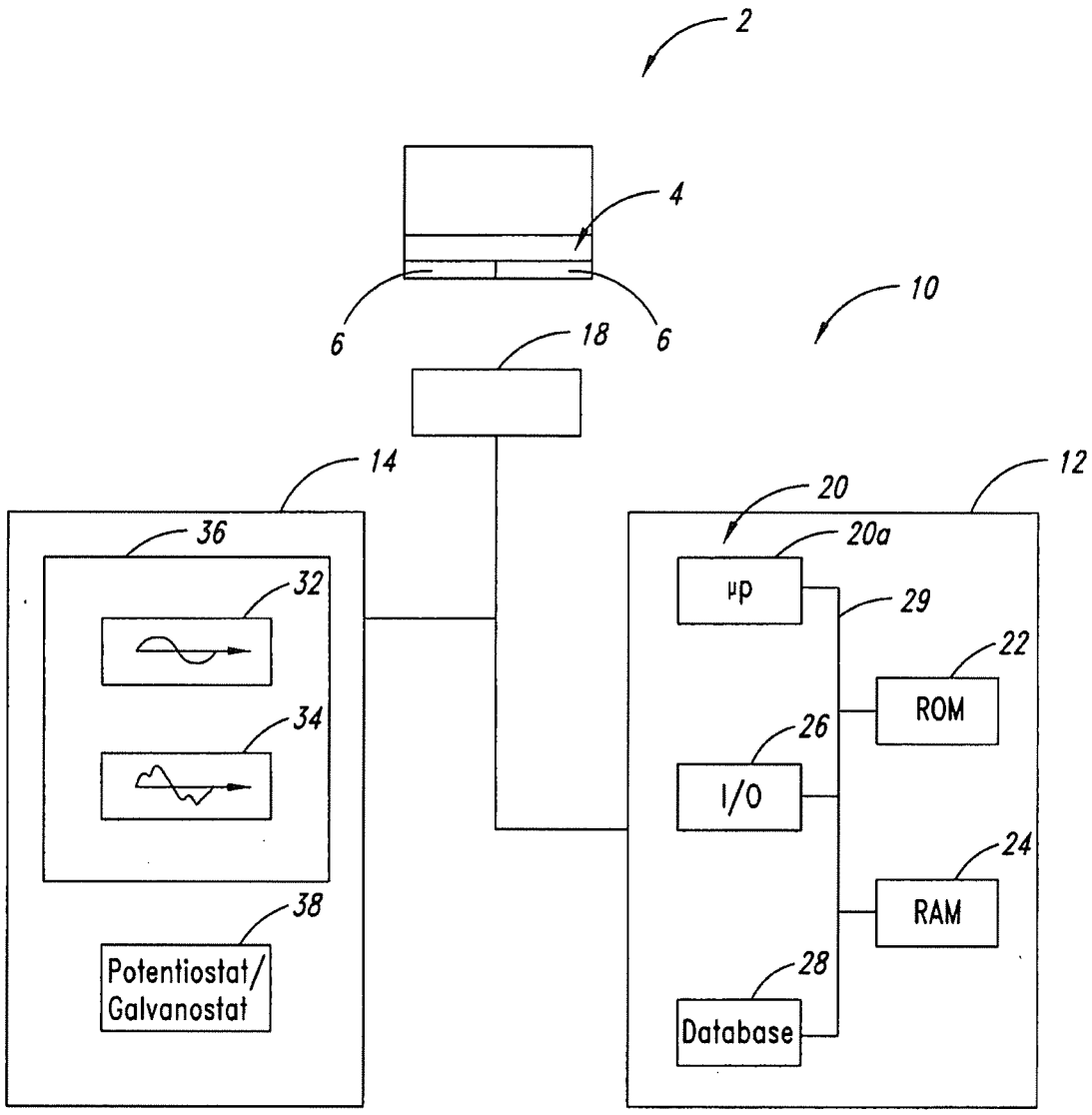

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14
12
20
36
20a
32
µp
29
22
ROM
34
26
I/O
24
RAM
38
Potentiostat/
Galvanostat
28
Database

FIG. 1

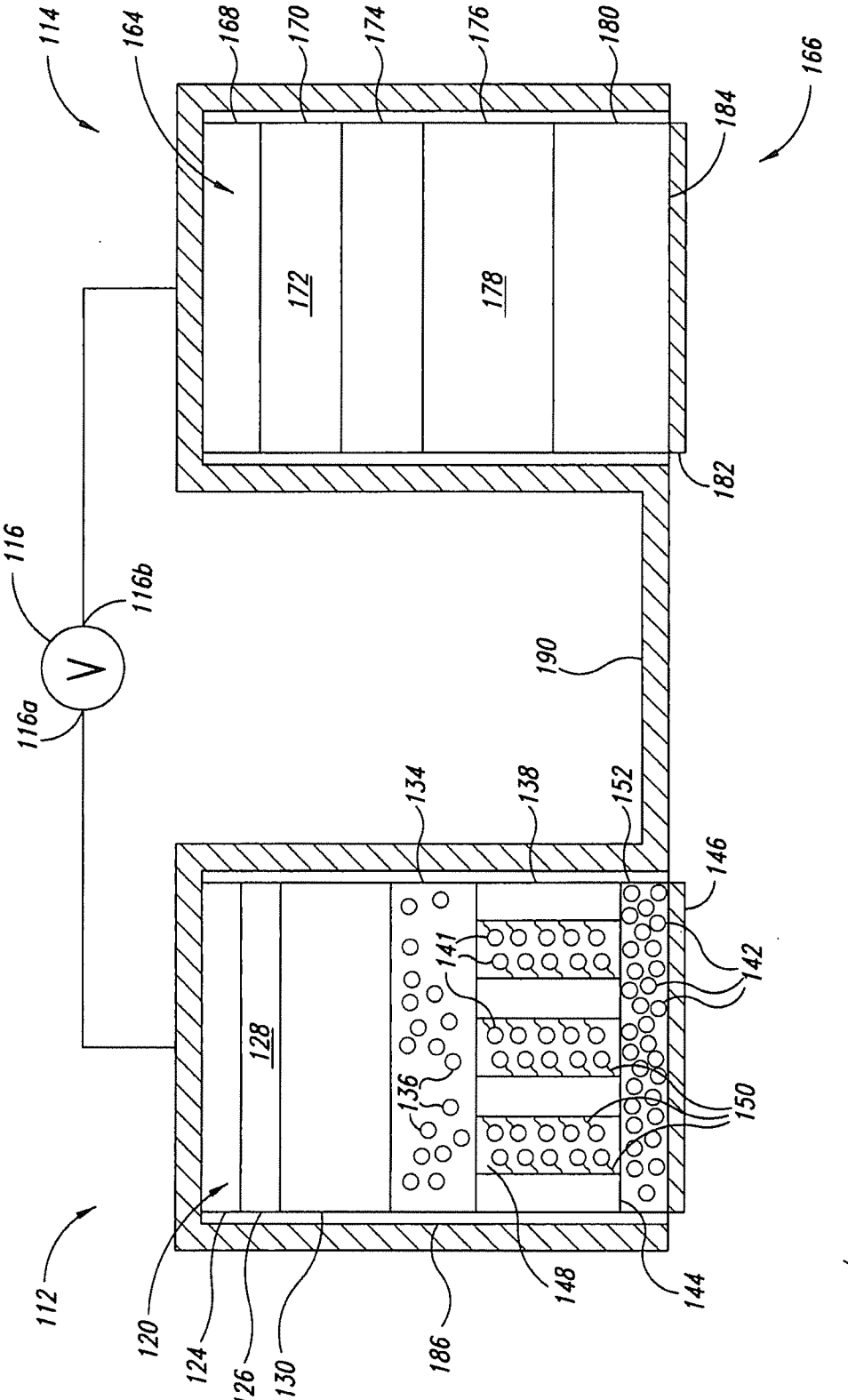

110
114
164
168
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172
178
182
116
116b
V
116a
190
134
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152
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142
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144
122

FIG. 2

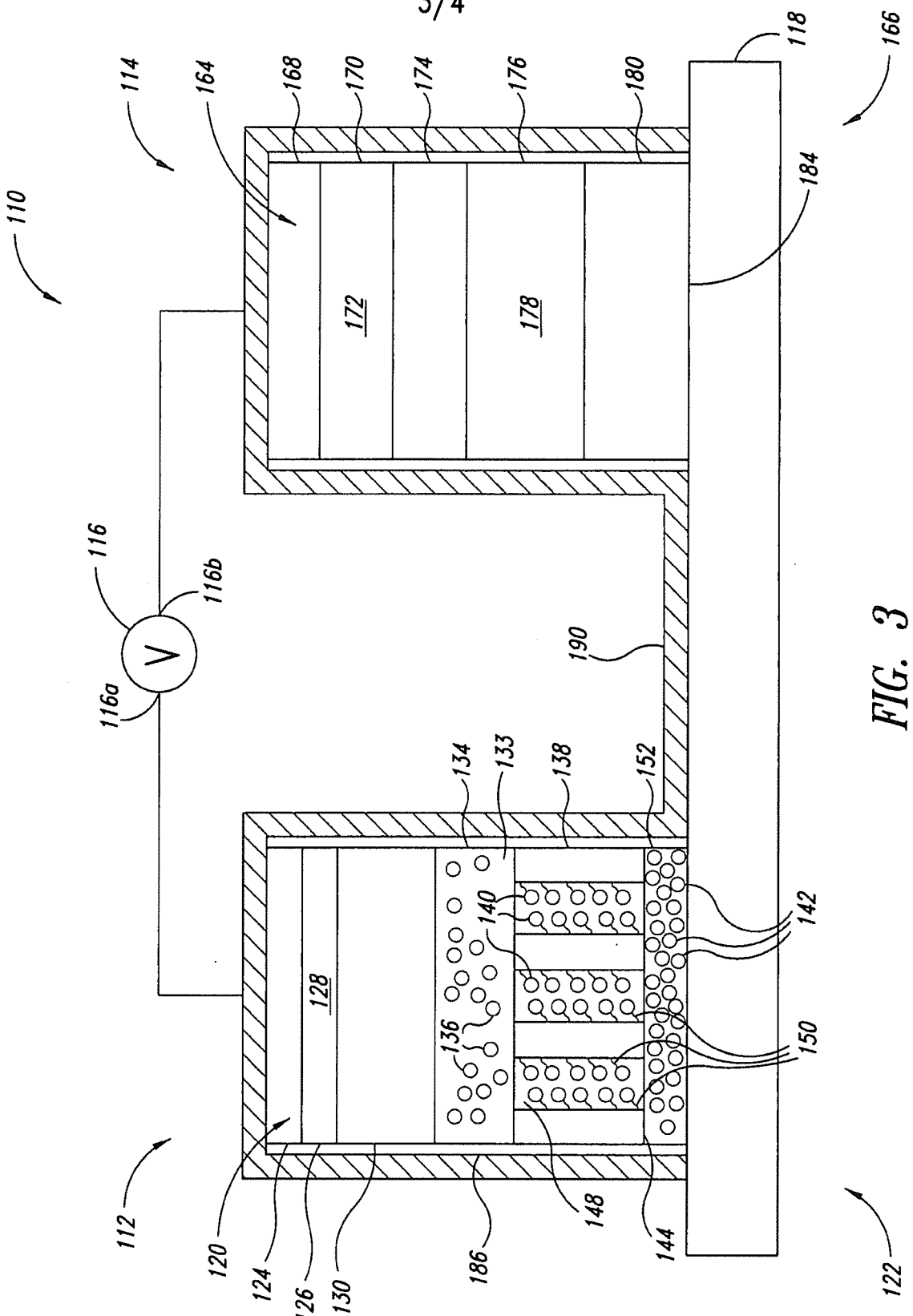

110
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116a
116b
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V

FIG. 3

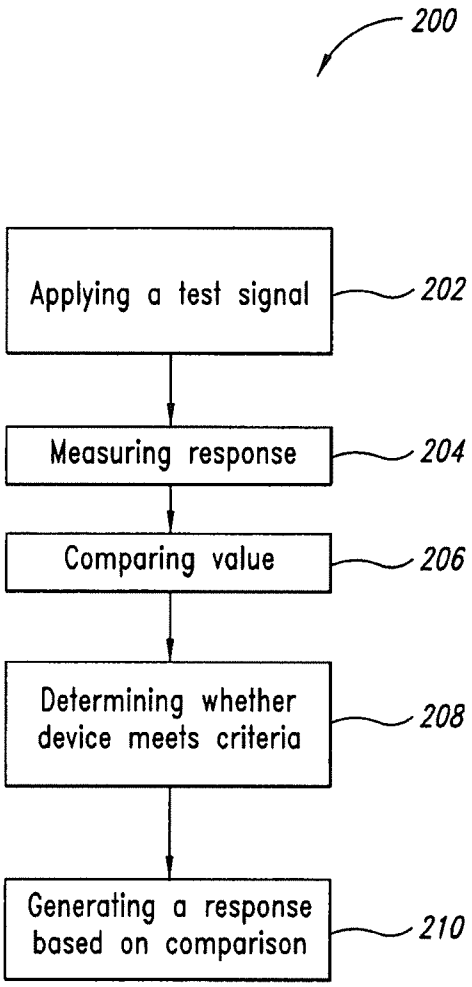

200
Applying a test signal
202
Measuring response
204
Comparing value
206
Determining whether device meets criteria
208
Generating a response based on comparison
210

FIG. 4